

L Number	Hits	Search Text	DB	Time stamp
5	47	(US-6484064-\$ or US-5659467-\$ or US-5655110-\$ or US-6532392-\$ or US-6397114-\$ or US-6539267-\$ or US-6486081-\$ or US-6017143-\$ or US-5015492-\$ or US-6580960-\$ or US-6509197-\$ or US-6383402-\$ or US-6275740-\$ or US-6119047-\$ or US-5658418-\$ or US-6524873-\$ or US-6392434-\$ or US-6327555-\$ or US-6314379-\$ or US-6265232-\$ or US-5828778-\$ or US-6581191-\$ or US-6553548-\$ or US-5625816-\$ or US-6542837-\$ or US-6532182-\$).did. or (US-6456951-\$ or US-6304791-\$ or US-6202037-\$ or US-6184048-\$ or US-6154714-\$ or US-5991699-\$ or US-5923553-\$ or US-5889674-\$ or US-5646870-\$ or US-5576223-\$ or US-5886909-\$ or US-6587744-\$ or US-6535776-\$ or US-6363294-\$ or US-6161054-\$ or US-6542830-\$ or US-6473665-\$ or US-5985497-\$ or US-5844850-\$).did. or (US-20010020194-\$ or US-20020121915-\$).did.	USPAT; US-PGPUB	2003/07/18 16:37
10	6	((US-6484064-\$ or US-5659467-\$ or US-5655110-\$ or US-6532392-\$ or US-6397114-\$ or US-6539267-\$ or US-6486081-\$ or US-6017143-\$ or US-5015492-\$ or US-6580960-\$ or US-6509197-\$ or US-6383402-\$ or US-6275740-\$ or US-6119047-\$ or US-5658418-\$ or US-6524873-\$ or US-6392434-\$ or US-6327555-\$ or US-6314379-\$ or US-6265232-\$ or US-5828778-\$ or US-6581191-\$ or US-6553548-\$ or US-5625816-\$ or US-6542837-\$ or US-6532182-\$).did. or (US-6456951-\$ or US-6304791-\$ or US-6202037-\$ or US-6184048-\$ or US-6154714-\$ or US-5991699-\$ or US-5923553-\$ or US-5889674-\$ or US-5646870-\$ or US-5576223-\$ or US-5886909-\$ or US-6587744-\$ or US-6535776-\$ or US-6363294-\$ or US-6161054-\$ or US-6542830-\$ or US-6473665-\$ or US-5985497-\$ or US-5844850-\$).did. or (US-20010020194-\$ or US-20020121915-\$).did.) and (server\$1 with (database\$1 or (data adj base\$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/18 16:46

11	7	((US-6484064-\$ or US-5659467-\$ or US-5655110-\$ or US-6532392-\$ or US-6397114-\$ or US-6539267-\$ or US-6486081-\$ or US-6017143-\$ or US-5015492-\$ or US-6580960-\$ or US-6509197-\$ or US-6383402-\$ or US-6275740-\$ or US-6119047-\$ or US-5658418-\$ or US-6524873-\$ or US-6392434-\$ or US-6327555-\$ or US-6314379-\$ or US-6265232-\$ or US-5828778-\$ or US-6581191-\$ or US-6553548-\$ or US-5625816-\$ or US-6542837-\$ or US-6532182-\$).did. or (US-6456951-\$ or US-6304791-\$ or US-6202037-\$ or US-6184048-\$ or US-6154714-\$ or US-5991699-\$ or US-5923553-\$ or US-5889674-\$ or US-5646870-\$ or US-5576223-\$ or US-5886909-\$ or US-6587744-\$ or US-6535776-\$ or US-6363294-\$ or US-6161054-\$ or US-6542830-\$ or US-6473665-\$ or US-5985497-\$ or US-5844850-\$).did. or (US-20010020194-\$ or US-20020121915-\$).did.) and server\$1 "5844850"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 16:46
12	12		USPAT	2003/07/18 18:39
13	184	(702/81).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 18:52
14	51	(702/83).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 18:52
15	281	(702/84).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 18:52
16	1012	(702/188).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 18:52
17	313	(702/189).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 18:52
18	75	((702/84).CCLS.) and (cause\$2 with (drift\$3 or defect\$5 or error\$1 or variation\$1 or variance\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 18:53
19	33	((702/188).CCLS.) and (cause\$2 with (drift\$3 or defect\$5 or error\$1 or variation\$1 or variance\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 18:53
20	46	((702/189).CCLS.) and (cause\$2 with (drift\$3 or defect\$5 or error\$1 or variation\$1 or variance\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/18 18:53
-	3425	process with drift\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/07/10 16:16

-	187	(process with drift\$3 with cause\$1) and (categor\$3 or feature\$1 or profile\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:16
-	377	(process with drift\$3) and (cause with drift\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:16
-	789	(process with drift\$3) and (cause\$1 with drift\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 17:23
-	555	((process with drift\$3) and (cause\$1 with drift\$3)) and (compare\$1 or comparison\$1 or comparing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:20
-	331	((process with drift\$3) and (cause\$1 with drift\$3)) and (compare\$1 or comparison\$1 or comparing) and (manufactur\$5 or fabricat\$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:56
-	21	((process with drift\$3) and (cause\$1 with drift\$3)) and ((advanced near1 process near1 control\$1) or catalyst or (semiconductor near2 equipment near2 material\$1) or (computer near2 integrated near manufatur\$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:28
-	0	6484064.URPN.	USPAT	2003/07/10 16:28
-	4	("5862055" "6255125" "6277658" "6292708").PN.	USPAT	2003/07/10 16:36
-	14059	(advanced with micro with devices) .asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:39
-	181	((advanced with micro with devices) .asn.) and drift\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 14:31
-	35	((advanced with micro with devices) .asn.) and (drift\$3 with process\$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/11 08:43
-	62096	process with variation\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:56
-	2905	(process with variation\$1) and drift\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:57
-	533	((process with variation\$1) and drift\$3) and (cause\$1 with drift\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:58
-	77	((process with variation\$1) and drift\$3) and ((cause\$1 with drift\$3) with (detect\$5 or determin\$6))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 16:59

-	86	(process with drift\$3) and ((cause\$1 with drift\$3) with (detect\$5 or determin\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/11 08:02
-	43	(process with drift\$3) and ((cause\$1 with variation\$3) with (detect\$5 or determin\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/11 08:02
-	1863	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6)) and (process\$3 with (error\$1 or drift\$3))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/11 08:48
-	479	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with (error\$1 or drift\$3))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/11 08:49
-	82	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with (error\$1 or drift\$3) with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/14 17:00
-	126	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1) with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/14 19:20
-	30	(716/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1) with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/14 18:57
-	3	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with variance\$1 with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/14 19:19
-	3	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3)) and (cause\$1 with variance\$1 with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/14 19:19
-	201	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 7160?\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 09:42

-	58	drift adj analy\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/14 21:47
-	104	(438/\$.cccls. or 700/\$.cccls. or 702/\$.cccls. or 7160?\$.cccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6)) and (batch\$2 or lot\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 09:41
-	117	(438/\$.cccls. or 700/\$.cccls. or 702/\$.cccls. or 7160?\$.cccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6)) and (yield\$1 characterist\$6 with thread\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 09:41
-	4001		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:37
-	1073	characterist\$6 near2 thread\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:38
-	519	(characterist\$6 near2 thread\$1) and (manufactur\$6 or fabricat\$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:38
-	358	(characterist\$6 near2 thread\$1) and (manufactur\$6 or fabricat\$6) and process\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:39
-	111	(characterist\$6 near2 thread\$1) and (manufactur\$6 or fabricat\$6) and process\$3 and (drift\$3 or variance\$1 or error or defect\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:43
-	28	(characterist\$6 near2 thread\$1) and (manufactur\$6 or fabricat\$6) and process\$3 and (drift\$3 or variance\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:46
-	4	(characterist\$6 near2 thread\$1) and ((manufactur\$6 or fabricat\$6) with (wafer\$1 or semiconductor\$1 or chip\$1)) and process\$3 and (drift\$3 or variance\$1 or error or defect\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:45
-	5	(characterist\$6 near2 thread\$1) and ((manufactur\$6 or fabricat\$6) with (wafer\$1 or semiconductor\$1 or chip\$1)) and process\$3 and (drift\$3 or variance\$1 or error or defect\$1 or variation\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:45
-	73	(characterist\$6 near2 thread\$1) and (process\$3 with (drift\$3 or variance\$1 or error\$1 or variation\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/15 10:47

-	86	(characterist\$6 near2 thread\$1) and (process\$3 with (drift\$3 or variance\$1 or error\$1 or variation\$1 or defect\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB;	2003/07/15 10:47
-	3	"6438438"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB;	2003/07/15 19:41
-	3	"6393602"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB;	2003/07/15 19:42
-	2	"6180424"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB;	2003/07/15 19:42
-	37	(US-6484064-\$ or US-5659467-\$ or US-5655110-\$ or US-6532392-\$ or US-6397114-\$ or US-6539267-\$ or US-6486081-\$ or US-6017143-\$ or US-5015492-\$ or US-6580960-\$ or US-6509197-\$ or US-6383402-\$ or US-6275740-\$ or US-6119047-\$ or US-5658418-\$ or US-6524873-\$ or US-6392434-\$ or US-6327555-\$ or US-6314379-\$ or US-6265232-\$ or US-5828778-\$ or US-6581191-\$ or US-6553548-\$ or US-5625816-\$ or US-6542837-\$ or US-6532182-\$).did. or (US-6456951-\$ or US-6304791-\$ or US-6202037-\$ or US-6184048-\$ or US-6154714-\$ or US-5991699-\$ or US-5923553-\$ or US-5889674-\$ or US-5646870-\$ or US-5576223-\$).did. or (US-20010020194-\$).did.	USPAT; US-PGPUB	2003/07/16 13:00
-	28	((US-6484064-\$ or US-5659467-\$ or US-5655110-\$ or US-6532392-\$ or US-6397114-\$ or US-6539267-\$ or US-6486081-\$ or US-6017143-\$ or US-5015492-\$ or US-6580960-\$ or US-6509197-\$ or US-6383402-\$ or US-6275740-\$ or US-6119047-\$ or US-5658418-\$ or US-6524873-\$ or US-6392434-\$ or US-6327555-\$ or US-6314379-\$ or US-6265232-\$ or US-5828778-\$ or US-6581191-\$ or US-6553548-\$ or US-5625816-\$ or US-6542837-\$ or US-6532182-\$).did. or (US-6456951-\$ or US-6304791-\$ or US-6202037-\$ or US-6184048-\$ or US-6154714-\$ or US-5991699-\$ or US-5923553-\$ or US-5889674-\$ or US-5646870-\$ or US-5576223-\$).did. or (US-20010020194-\$).did.) and identif\$5	USPAT	2003/07/16 13:00

-	29	((US-6484064-\$ or US-5659467-\$ or US-5655110-\$ or US-6532392-\$ or US-6397114-\$ or US-6539267-\$ or US-6486081-\$ or US-6017143-\$ or US-5015492-\$ or US-6580960-\$ or US-6509197-\$ or US-6383402-\$ or US-6275740-\$ or US-6119047-\$ or US-5658418-\$ or US-6524873-\$ or US-6392434-\$ or US-6327555-\$ or US-6314379-\$ or US-6265232-\$ or US-5828778-\$ or US-6581191-\$ or US-6553548-\$ or US-5625816-\$ or US-6542837-\$ or US-6532182-\$).did. or (US-6456951-\$ or US-6304791-\$ or US-6202037-\$ or US-6184048-\$ or US-6154714-\$ or US-5991699-\$ or US-5923553-\$ or US-5889674-\$ or US-5646870-\$ or US-5576223-\$).did. or (US-20010020194-\$).did.) and identif\$5 ((advanced with micro with devices) .asn.) and drift\$3 and identifier\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 13:00
-	14	((advanced with micro with devices) .asn.) and drift\$3 and identifier\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 14:33
-	2	((advanced with micro with devices) .asn.) and drift\$3 and thread\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 14:34
-	852	((advanced with micro with devices) .asn.) and (cause\$2 with (drift\$3 or defect\$5 or error\$1 or variation\$1 or variance\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 14:35
-	129	((advanced with micro with devices) .asn.) and (cause\$2 with (drift\$3 or defect\$5 or error\$1 or variation\$1 or variance\$1) with (determin\$6 or detect\$7))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 17:27
-	216	(700/110).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 17:28
-	750	(700/121).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 19:32
-	153	(process\$1 with drift\$1) and (cause\$2 with (drift\$3 or defect\$5 or error\$1 or variation\$1 or variance\$1) with (determin\$6 or detect\$7))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/18 18:53
-	1813	(process\$1 with (variance\$1 or variation\$1)) and (cause\$2 with (drift\$3 or defect\$5 or error\$1 or variation\$1 or variance\$1) with (determin\$6 or detect\$7))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 18:02
-	2	("5624590" "5848842").PN.	USPAT	2003/07/16 18:03
-	1	6268270.URPN.	USPAT	2003/07/16 18:03
-	307	(700/108).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 19:32

843	(700/117).CCLS.	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 19:32
150	(700/109).CCLS.	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 20:23
40	((700/121).CCLS.) and drift\$3	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 20:33
13	((700/121).CCLS.) and drift\$3 and (cause\$1 with (variance\$1 or variation\$1 or drift\$1))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 20:43
167	((700/121).CCLS.) and process\$3 and (cause\$1 with (variance\$1 or variation\$1 or drift\$1 or error or defect\$1))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 20:50
22	((700/121).CCLS.) and drift\$3 and (cause\$1 with (variance\$1 or variation\$1 or drift\$1 or error or defect\$1))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 20:44
53	((700/121).CCLS.) and process\$3 and (cause\$1 with (variance\$1 or variation\$1 or drift\$1 or error or defect\$1) with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/16 20:53
53	((700/121).CCLS.) and (cause\$1 with (variance\$1 or variation\$1 or drift\$1 or error or defect\$1) with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 10:41
112	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 716/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6)) and (batch\$2 or lot\$1)	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 09:42
132	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 716/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6)) and yield\$1	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 09:43
235	(438/\$.ccls. or 700/\$.ccls. or 702/\$.ccls. or 716/\$.ccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6))	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:28

		18	(438/\$.cccls. or 700/\$.cccls. or 702/\$.cccls. or 716/\$.cccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6) with compar\$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 10:32
		6	(438/\$.cccls. or 700/\$.cccls. or 702/\$.cccls. or 716/\$.cccls.) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1)) and (process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$9 with compar\$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 10:34
		7	((700/121).CCLS.) and (caus\$4 with (variance\$1 or variation\$1 or drift\$1 or error or defect\$1) with (determin\$7 or detect\$6 or identif\$9) with compar\$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 10:43
		7	((700/121).CCLS.) and (caus\$4 with (variance\$1 or variation\$1 or drift\$1 or error\$1 or defect\$1) with (determin\$7 or detect\$6 or identif\$9) with compar\$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 10:43
		2952	(process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) and ((error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$8)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:31
		230	(process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) and ((error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$8) and (compar\$7 with characteristic\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 15:32
		59	(process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and (cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) and ((error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$8) and (compar\$7 with characteristic\$1) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:02
		7	(process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and ((cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) with compar\$6) and ((error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with identif\$8) and (compar\$7 with characteristic\$1) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:04

-	10	(process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and ((cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) with compar\$6) and identif\$8 and (compar\$7 with characteristic\$1) and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:05
-	65	(process\$3 with (error\$1 or drift\$3 or variation\$1 or variance\$1)) and ((cause\$1 with (error\$1 or drift\$3 or defect\$1 or variance\$1 or variation\$1) with (determin\$7 or detect\$6 or identif\$8)) with compar\$6) and identif\$8 and ((wafer\$1 or semiconductor\$1 or chip\$1) with (manufactur\$5 or fabricati\$5 or produc\$6 or defect\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/17 16:06